

Dual N-Channel 12-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω) TYP.	I _D (A) a	Q _g (TYP.)			
12	0.0021 at $V_{GS} = 4.5V$	26	31 nC			
	0.0032 at V _{GS} = 2.5 V	22	31110			

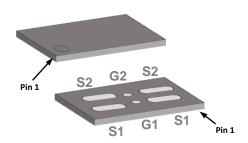
FEATURES

- DT-Trench Power MOSFET
- 100 % R_a and UIS tested
- ESD Protection Diode Embedded

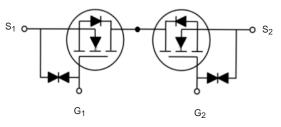


APPLICATIONS

- Battery Management
- POL Applications
- Battery Protection Applications



CSP-6 Dual Pin Configuration



N-Channel MOSFET

N-Channel MOSFET

PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	12	V		
Gate-Source Voltage	V _{GS}	±8			
	T _C = 25 °C		26		
Continuous Dunis Comment (T. 150 °C)	T _C = 70 °C		19		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	9.0 ^{b, c}		
	T _A = 70 °C		5.4 b, c		
Pulsed Drain Current (t = 300 μs)		I _{DM}	105	A	
Continuous Source-Drain Diode Current	T _C = 25 °C		26		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	5.2 b, c		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	25		
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	8.9	mJ	
	T _C = 25 °C		16		
Mayimum Bayyar Dissination	T _C = 70 °C		10.2	_ w	
Maximum Power Dissipation	T _A = 25 °C	P _D	2.1 ^{b, c}	VV	
	T _A = 70 °C		1.3 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to 150	°C	
Soldering Recommendations (Peak Temperatur		260			

THERMAL RESISTANCE RATINGS								
PARAMETER	SYMBOL	TYPICAL	MAXIMUM	UNIT				
Maximum Junction-to-Ambient b, f	t ≤ 10 s	R _{thJA}	28	45	°C/W			
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	4	6				

Notes

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. The CSP-6 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



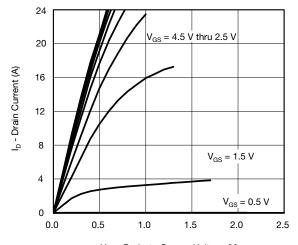


PARAMETER	SYMBOL	SYMBOL TEST CONDITIONS		TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	12	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A	-	20	-	mV/° C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu\text{A}$	-	-4.6	-	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.4	-	1.4	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$	-	-	± 10	μΑ
Zava Cata Valtaga Dvain Cuwant		V _{DS} = 12 V ,V _{GS} = 0 V	-	-	1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 10 V ,V _{GS} = 0 V, T _J = 55 °C	-	-	10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	26	-	-	Α
D : 0		V _{GS} = 4.5 V, I _D = 6 A	-	0.0021	0.0028	0
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 2.5 \text{ V}, I_D = 6A$	-	0.0032	0.0059	Ω
Dynamic ^b						
Input Capacitance	C _{iss}		-	3050	-	- pF
Output Capacitance	C _{oss}	$V_{DS} = 6 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	1010	-	
Reverse Transfer Capacitance	C _{rss}		-	603	-	
Total Gate Charge	Qg		-	39	-	nC
Gate-Source Charge	Q_{gs}	$V_{DS} = 6 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 6 \text{ A}$	-	5	-	
Gate-Drain Charge	Q _{gd}		-	9	-	
Gate Resistance	Rg	f = 1 MHz	-	1.60	-	Ω
Turn-On Delay Time	t _{d(on)}		-	29	=.	
Rise Time	t _r	$V_{DD} = 6 \text{ V}, R_L = 1.5 \Omega$	-	13	-	ns
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 6 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1\Omega$	-	180	-	
Fall Time	t _f		-	68	-	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	-	26	^
Pulse Diode Forward Current ^a	I _{SM}		-	-	105	Α
Body Diode Voltage	V _{SD}	I _S = 3 A	-	0.70	1.2	V
			-			•

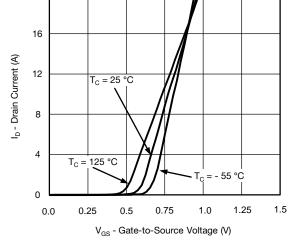
- a. Pulse test; pulse width $\leq\!300~\mu\text{s},$ duty cycle $\leq\!2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. $T_{CASE} = 25$ °C. Expected voltage stress during 100 % UIS test. Production datalog is not available.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

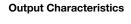


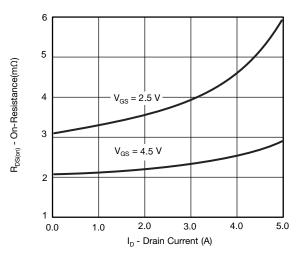


 \mathbf{V}_{DS} - Drain-to-Source Voltage (V)

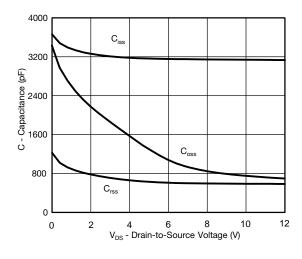


Transfer Characteristics

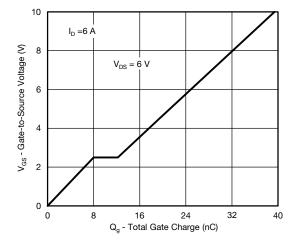




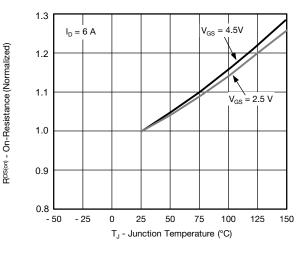
On-Resistance vs. Drain Current



Capacitance

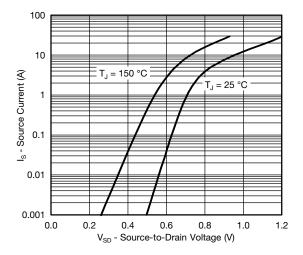


Gate Charge

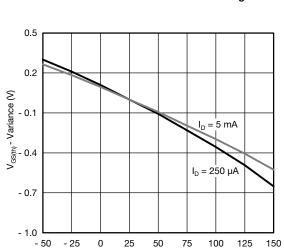


On-Resistance vs. Junction Temperature



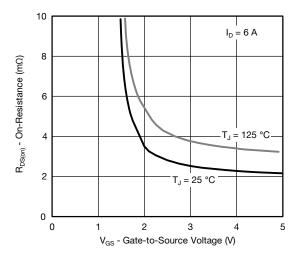


Source-Drain Diode Forward Voltage

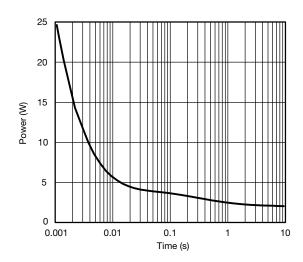


Threshold Voltage

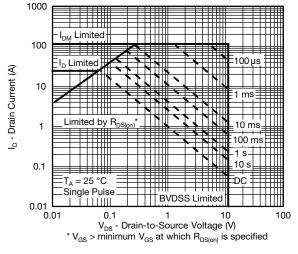
T_J - Temperature (°C)



On-Resistance vs. Gate-to-Source Voltage

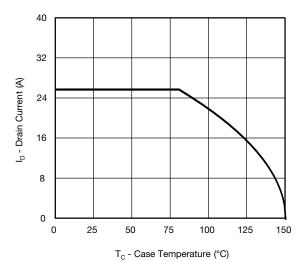


Single Pulse Power, Junction-to-Ambient

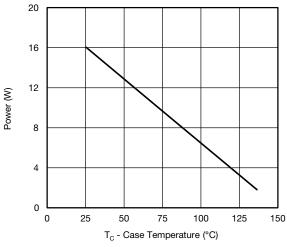


Safe Operating Area



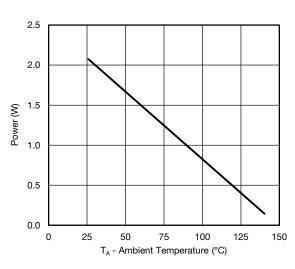


Current Derating*



Power, Junction-to-Case

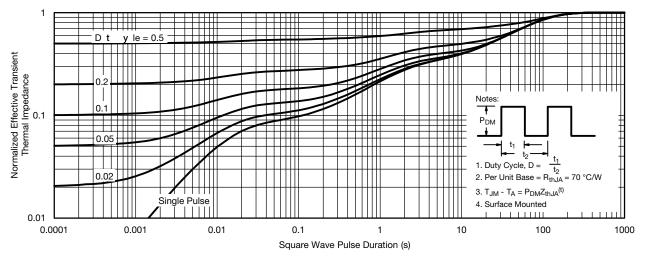




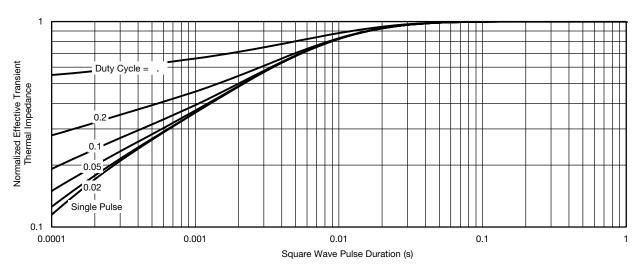
Power, Junction-to-Ambient

 $^{^{\}star}$ The power dissipation P_D is based on $T_{J (max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





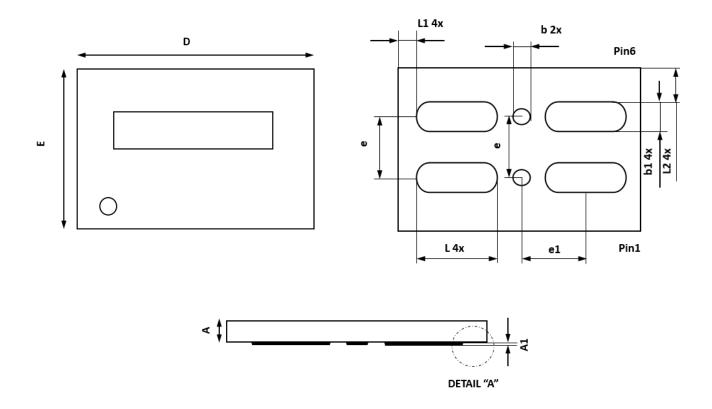
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



CSP-6 Pad Dual PACKAGE INFORMATION



Symbol	Dimension In Millimeters			Dimension In Inches		
	Min	Normal	Max	Min	Normal	Max
Α	0.320		0.380	0.013		0.015
A 1			0.005			0.000
D	3.000	3.050	3.100	0.118	0.120	0.122
E	2.000	2.050	2.100	0.079	0.081	0.083
b	0.220	0.250	0.280	0.009	0.010	0.011
b1	0.320	0.350	0.380	0.013	0.014	0.015
L	0.975	1.005	1.035	0.038	0.040	0.041
L1	0.095	0.145	0.195	0.004	0.006	0.008
L2	0.400	0.450	0.500	0.016	0.018	0.020
е	0.800REF			0.031REF		
e1	0.875BSC			0.035BSC		





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